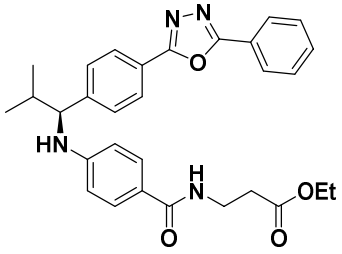
WHAT IS CLAIMED IS:

1. A crystalline form of a compound of formula (1),



(1)

characterized by an X-ray diffraction (XRD) pattern having peaks at about 14.2, 15.6, 16.4, 20.1, 20.5 and 21.2° ± 0.2° 2θ.

2. The crystalline form of claim 1, wherein the XRD pattern further has peaks at about 17.4, 21.7 or 23.7° ± 0.2° 2θ.

3. The crystalline form of claim 1, wherein the XRD pattern is substantially as depicted in any of FIG. 1 to FIG. 4.